

IN THE SPECIFICATION

Please replace the paragraph beginning at page 2, line 11, with the following amended paragraph:

Recent work by M. Brodie et al., (e.g., “Optimizing probe selection for fault localization,” Distributed Systems Operation and Management, 2001; “Intelligent Probing: A Cost-Efficient Approach to Fault Diagnosis in Computer Networks,” IBM Systems Journal 41 (3): 372-385; and U.S. patent application identified as Serial No. 10/676,244, ~~(attorney docket no. YOR920030250US1)~~ now U.S. Patent No. 6,167,998, filed on September 30, 2003 and entitled “Problem Determination Using Probing.”) proposed to use probing for diagnosis. However, the work focused mainly on pre-planned, fixed probe sets, which are scheduled to run periodically. Because the probe set is computed off-line, it needs to be able to diagnose all possible problems which might occur. However in practice, many of these problems may in fact never happen, and running the complete set of pre-planned probes might be quite wasteful.

Please replace the paragraph beginning at page 8, line 1, with the following amended paragraph:

(1) Accept as an input a set S of probes available in a system. Find an optimal subset LPS of S that is capable of diagnosing exactly the same set of problems as the probes in S. This step may utilize existing probe planning techniques. By way of example, this step may employ existing probe planning techniques using a dependency matrix to describe the relationship between probe outcomes and states of system components, for example, see work by M. Brodie et al.: “Optimizing probe selection for fault localization,” Distributed Systems Operation and Management, 2001; “Intelligent Probing: A Cost-Efficient Approach to Fault Diagnosis in Computer Networks,” IBM Systems Journal 41 (3): 372-385; and U.S. patent application identified as Serial No. 10/676,244, ~~(attorney docket no. YOR920030250US1)~~ now U.S. Patent No. 6,167,998, filed on September 30, 2003 and entitled “Problem Determination Using Probing,” the disclosures of which are incorporated by reference herein.

Please replace the paragraph beginning at page 14, line 23, with the following amended paragraph:

In the planning phase, the dependency matrix 801 described above is passed to probe planning tool 802. The probe planning tool generates DPS 803 and LPS 804. It is to be appreciated

that one example of an algorithm for use in LPS selection may be the algorithm described in the U.S. patent application identified as Serial No. 10/676,244, (~~attorney docket no. YOR920030250US1~~) now U.S. Patent No. 6,167,998, filed on September 30, 2003 and entitled "Problem Determination Using Probing." A process for DPS construction is described above in the context of FIG. 5.